

Notice of References Cited		Application/Control No. 10/550,842	Applicant(s)/Patent Under Reexamination CHUNG ET AL.	
		Examiner Frederick J. Parker	Art Unit 1792	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C US-6,153,263	11-2000	Haruta et al.	427/261
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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